

LIST OF REFERENCES CITED BY APPLICANT

(Use Several Sheets if Necessary)

DOCKET NO.: 9643/0L339      SERIAL NO: 10/088,719  
 APPLICANT: Takako FUJII      FILING DATE: March 21, 2002  
                                   CONFIRMATION NO:

U.S. PATENT DOCUMENTS

<u>*EXAMINER INITIALS</u>	<u>DOCUMENT NUMBER</u>	<u>DATE</u>	<u>NAME</u>	<u>CLASS</u>	<u>SUBCLASS</u>	<u>FILING DATE</u>
fw	1. 5,390,512	02/21/95	Mista	66	205	08/09/93

FOREIGN PATENT DOCUMENTS

<u>*EXAMINER INITIALS</u>	<u>DOCUMENT NUMBER</u>	<u>DATE</u>	<u>COUNTRY</u>	<u>CLASS</u>	<u>SUBCLASS</u>	<u>TRANSLATION YES</u>	<u>NO</u>
fw	2. 99/53779	10/28/99	WO	A41 C	1/00	Abstract Only	_____
fw	3. 1136001A	09/26/01	EP	A41 C	1/00	_____	_____
fw	4. 1016351A	07/05/00	EP	A41 B	11/00	Abstract Only	_____
fw	5. 98/21987	05/28/98	WO	A41 C	1/00	Partial Translation	_____
fw	6. 02182903A	07/17/90	JPO	A 41 C	1/00	Partial Translation	_____
fw	7. 2-30318U	02/27/90	JPO	A 61 F	5/02	Partial Translation	_____
fw	8. 6-12412U	02/18/94	JPO	A 41 C	1/00	Partial Translation	_____
fw	9. 64-37407U	03/07/89	JPO	A 41 C	1/02	Partial Translation	_____
fw	10. 3061048U	06/16/99	JPO	A 41 C	1/00	Partial Translation	_____

OTHER REFERENCES  
(INCLUDING AUTHOR, TITLE DATE, PERTINENT PAGES, ETC.)

\*EXAMINER INITIALS \_\_\_\_\_  
11. \_\_\_\_\_

EXAMINER: Jeanne Wilke DATE CONSIDERED: 5/21/05

\*EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609; draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.